

<b>Notice of References Cited</b>	Application/Control No. 10/553,076		Applicant(s)/Patent Under Reexamination YONEMURA ET AL.	
	Examiner MEIYA LI		Art Unit 2811	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0030268	03-2002	Sakamoto et al.	257/700
*	B	US-6,233,817	05-2001	Ellis et al.	29/832
	C	US-			
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	K	US-			
	L	US-			
	M	US-			

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#### NON-PATENT DOCUMENTS

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